



Certificate of Analysis

ULTRAgrade™ Solution
Silicon ICP Standard
1000 µg/mL

Catalog Number: ICP-014
Lot Number: L00699
Job Number: J00011183
Lot Issue Date: 06/21/2010
Expiration Date: 07/31/2017

Starting Material: Ammonium Hexafluorosilicate
Starting Material Purity: 99.999%
Starting Material Lot No.: BH01549
Matrix: 2% nitric acid, with trace HF, in low TOC water (< 50 ppb)
Atomic Weight Si: 28.09

Certified Value: 1001 ± 2 µg/mL

This Certified Reference Material (CRM) was manufactured and verified in accordance with ULTRA's ISO 9001 registered quality system. The analyte concentrations were verified by our ISO 17025 accredited laboratory to be within ± 2.5%, when compared to calibration standards independently prepared using NIST SRM(s). The certified value and uncertainty value for each analyte is determined gravimetrically.

Classical Wet Assay Method: Theoretical, based on gravimetric measurements

Confirmation by Inductively Coupled Plasma Spectroscopy (ICP / ICP-MS) vs. NIST SRM 3150

ULTRA uses purified acids, 18 megohm double deionized water, calibrated Class A glassware & meticulously cleaned bottles in the manufacturing of ULTRAgrade standards. Balances used in the manufacturing of this standard are calibrated with weights traceable to NIST in compliance with ANSI/NCCL Z-540-1 and ISO 9001.

Trace Metallic Impurities in Solution Standard in µg/mL:

* Al	<0.005	ND	* Ga	<0.005	ND	n Nb		n S	
* Sb	<0.005	ND	n Ge			n Os		n Ta	
* As	<0.005	ND	n Au			* Pd	<0.005	ND	n Te
* Ba	<0.005	ND	n Hf			* P	<0.005	ND	n Tb
* Be	<0.005	ND	n Ho			* Pt	<0.005	ND	* Tl
* Bi	<0.005	ND	* In	<0.005	ND	* K	<0.005	ND	n Th
* B	<0.005	ND	n Ir			n Pr			n Tm
* Cd	<0.005	ND	* Fe	<0.005	ND	n Re			* Sn
* Ca	<0.005	ND	* La	<0.005	ND	n Rh			* Ti
n Ce			* Pb	<0.005	ND	n Rb			n W
n Cs			* Li	<0.005	ND	n Ru			n U
* Cr	<0.005	ND	n Lu			n Sm			* V
* Co	<0.005	ND	* Mg	<0.005	ND	n Sc			n Yb
* Cu	<0.005	ND	* Mn	<0.005	ND	* Se	<0.005	ND	n Y
n Dy			* Hg	<0.005	ND	s Si			* Zn
* Er	<0.005	ND	* Mo	<0.005	ND	* Ag	<0.005	ND	n Zr
* Eu	<0.005	ND	n Nd			* Na	<0.005	ND	
* Gd	<0.005	ND	* Ni	<0.005	ND	* Sr	<0.005	ND	

* - element checked for
ND - not detected

i - spectral interference
D - detected

n - not checked for
s - solution standard element

Density of Solution (measured at 22.0°C ± 0.5°C): 1.015 g/mL



ISO 9001 Registered Quality System – TUV USA

William J. Leary
Quality Assurance Manager